Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

REMARKS

This responds to the Office Action mailed on May 25, 2007.

No claims are amended, cancelled, or added; as a result, claims 29-43 remain pending in this application.

§102 Rejection of the Claims

Claims 29-37 were rejected under 35 U.S.C. § 102(e) for anticipation by Sato (U.S. 6,124,725).

Sato discusses a system in which a switch mechanism switches between operation of an electric characteristic test mechanism and a reliability test mechanism such that the electric and reliability test mechanisms are sequentially coupled to the contactor (prober) when the contactor is in contact with a wafer under test.

Sato does not teach concurrent operation of semiconductor test equipment and parametric test instrumentation, as is recited in the pending claims. More specifically, contactor 12 is cited as anticipating the claimed element of parametric test instrumentation in claim 29 and others, when a contactor or prober is defined in the pending application and claims as semiconductor test equipment (see, e.g. claim 32).

Further, the application teaches throughout that only after the contactor is in contact with the wafer under test does the Sato's switcher switch sequentially between an electric characteristic test mechanism and a reliability test mechanism (see, e.g., the Abstract, In. 13-18). Sato therefore fails to consider concurrent operation of semiconductor test equipment and parametric test instrumentation, as is recited in each of the pending claims.

The cited controller 35 is operable only to receive input from temperature sensors and control the temperature of the main chuck, and so also does not teach concurrent operation of semiconductor test equipment and parametric test instrumentation (see, col. 6, ln. 48-64).

Because no part of Sato appears to teach concurrent operation of semiconductor test equipment and parametric test instrumentation, as is recited in the pending claims, the pending claims 29-37 are believed to be allowable over the prior art. Reexamination and allowance of these pending claims is therefore respectfully requested.

Filing Date: April 13,2001 Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

Allowable Subject Matter

Claims 42 and 43 were allowed.

Claims 38-41 were objected to as being dependent upon a rejected base claim, but were indicated to be allowable if rewritten in independent form including all of the limitations of the base claim and any intervening claims.

These claims are not amended, as they depend from claims believed to be in condition for allowance as explained above.

RESERVATION OF RIGHTS

In the interest of clarity and brevity, Applicant may not have addressed every assertion made in the Office Action. Applicant's silence regarding any such assertion does not constitute any admission or acquiescence. Applicant reserves all rights not exercised in connection with this response, such as the right to challenge or rebut any tacit or explicit characterization of any reference or of any of the present claims, the right to challenge or rebut any asserted factual or legal basis of any of the rejections, the right to swear behind any cited reference such as provided under 37 C.F.R. § 1.131 or otherwise, or the right to assert co-ownership of any cited reference. Applicant does not admit that any of the cited references or any other references of record are relevant to the present claims, or that they constitute prior art. To the extent that any rejection or assertion is based upon the Examiner's personal knowledge, rather than any objective evidence of record as manifested by a cited prior art reference, Applicant timely objects to such reliance on Official Notice, and reserves all rights to request that the Examiner provide a reference or affidavit in support of such assertion, as required by MPEP § 2144.03. Applicant reserves all rights to pursue any cancelled claims in a subsequent patent application claiming the benefit of priority of the present patent application, and to request rejoinder of any withdrawn claim, as required by MPEP § 821.04.

Filing Date: April 13, 2001
Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING

CONCLUSION

Applicant respectfully submits that the claims are in condition for allowance, and notification to that effect is earnestly requested. The Examiner is invited to telephone Applicant's attorney at (612) 349-9581 to facilitate prosecution of this application.

If necessary, please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By their Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A. P.O. Box 2938

Minneapolis, MN 55402 (612) 349-9581

Date Ang 27 07

John M. Dahl

Reg. No. 44,639

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being filed using the USPTO's electronic filing system EFS-Wob, and is addressed to: Mail Stop Amendment, Commissioner of Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on this 2 days of August 2007.

Znahalosky W. Covicos

Name